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Approved N.Y. State ELAP #10879
ACCREDITED NVLAP Lab Code # 1187
Report Date: 10/29/01

ASBESTOS FIBER ANALYSIS BY TRANSMISSION ELECTRON MICROSCOPY (TEM)

With Fiber Identification by Selected-Area Electron Diffraction (SAED) and Energy-Dispersive X-RAY Spectroscopy (EDS)
Method: AHERA Final Rule, EPA Federal Register (40 CFR, Part 763), Vol. 52, No. 210, October 30, 1987

Sample Identification

Analysis Parameters

Project/Site: New Stuyvesant H.S., 345 Chambers St., NY, NY

TEM Sample No.: 5785 - 62423

Exterior & Interior of Building & Roof

Grid Openings Analyzed: 4

Date Received: 10/28/01

Average Grid Opening: 106.00 um

Project Sample No.: 14

Total Area Analyzed: 0.0450 mm2

Air Volume: 1928 liters

Analytical Sensitivity: 22.2 s/mm2
0.0044 s/cc

Filter Type: MCE 25 mm diam., Pore Size: 0.45 um

Effective Area: 385 mm2

FIBROUS PARTICULATES ANALYZED

Number Observed

CONCENTRATION

	<u>Number Observed</u>			<u>CONCENTRATION</u>			<u>Filter</u>		<u>Air</u>
	<u>Single</u>	<u>Bundles</u>	<u>Clusters</u>	<u>Matrix</u>	<u>Total.</u>	<u>Total</u>	<u>Struct/mm2</u>	<u>Struct/cc</u>	<u>ngm/m3</u>
	<u>Fibers</u>			<u>Struct.</u>	<u>Struct.</u>	<u>>=5um</u>			
Chrysotile Asbestos	0	0	0	0	0	0	0.0	0.0000	0
Amphibole Asbestos	0	0	0	0	0	0	0.0	0.0000	0
Ambiguous	0	0	0	0	0	0	0.0	0.0000	0
Total asbestos (includes ambiguous structures)					0	0	0.0	0.0000	0
Non-Asbestos	0	0	0	0	0	0	0.0	0.0000	N/A
No Identification	0	0	0	0	0	0	0.0	0.0000	N/A
Totals (All Structures)					0	0	0.0	0.0000	N/A

The estimated uncertainty of this analysis is 1 standard deviation.

Non-asbestos fiber i.d. (EDS/SAED): None detected

Amphibole Asbestos Type: None detected

The Analysis was carried out in accordance with the approved TEM method.
This laboratory is in compliance with the quality specified for the method.

Analyzed by:

Report Reviewed by:

Marek Peysakhov

Michael A. Gorycki, Ph.D.
Director of Electron Microscopy